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Electrical ratings 1

		Valu	Unit	
Symbol	Parameter	STP4NM60	STP4NM60 STD3NM60 STD3NM60-1	
V _{DS}	Drain-source voltage (V _{GS} = 0)	600)	V
V _{GS}	Gate- source Voltage	± 30)	V
۱ _D	Drain current (continuous) at T_C = 25°C	4 3		А
I _D	Drain current (continuous) at T _C = 100°C 2.52 1.9		А	
I _{DM} ⁽¹⁾	Drain current (pulsed)	16 12		Α
P _{TOT}	Total dissipation at T_{C} = 25°C	69	42	W
	Derating factor	0.55 0.33		W/°C
dv/dt (2)	Peak diode recovery voltage slope	15		V/ns
Тj	Operating junction temperature -65 to 150		°C	
T _{stg}	Storage temperature	-05 10	°C	

1. Pulse width limited by safe operating area

2. $I_{SD} \leq 3 \text{ A}, \text{ di/dt} \leq 400 \ \mu\text{A}, \ V_{DD} \leq V_{(BR)DSS}, \ Tj \leq T_{JMAX}.$

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Table 3.	Thermal data

	Symbol	Parameter	Value		
	Symbol		То-220	DPAK / IPAK	Unit
	Rthj-case	Thermal resistance junction-case max	1.82	3	°C/W
10	Rthj-amb	Thermal resistance junction-ambient max	62.5		°C/W
SOlt	Тı	Maximum lead temperature for soldering purpose	300		°C
00					
	Table 4.	Avalanche characteristics			
	Symbol	Parameter		Value	Unit

Fable 4.Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AR}	Avalanche current, repetitive or not-repetitive (pulse width limited by T_{jmax})	1.5	А
E _{AS}	Single pulse avalanche energy (starting T _j = 25 °C, I _D = I _{AR} , V _{DD} = 50 V)	200	mJ



Electrical characteristics 2

(T_{CASE}= 25 °C unless otherwise specified)

	On/on states					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_{D} = 250 \ \mu A, \ V_{GS} = 0$	600			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V_{DS} = max rating V_{DS} = max rating, T_{C} = 125°C			1 10	μΑ μΑ
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	$V_{GS} = \pm 20V$		21	±5	μA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	3	4	5	V
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10 V, I _D = 1.5 A	61	1.3	1.5	Ω
Table 6.	Dynamic	olete				
Symbol	Baramatar	Test conditions	Min	Tun	Mox	Unit

Table 5. **On/off states**

Table 6. Dynamic

	Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
	9 _{fs} ⁽¹⁾	Forward transconductance	$V_{DS} = 15 V_{, I_{D}} = 1.5 A$	-	2.7	-	S
	C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 25 V, f = 1 MHz, V _{GS} = 0	-	324 132 7.4	-	pF pF pF
	t _{d(on)} t _r t _{d(off)} t _f	Turn-on delay time Rise time Turn-off delay time Fall time	$V_{DD} = 300 \text{ V}, I_D = 1.5 \text{ A}$ $R_G = 4.7 \Omega V_{GS} = 10 \text{ V}$ (see <i>Figure 15</i>)	-	9 4 16.5 10.5	-	ns ns ns ns
0650,	Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 480 \text{ V}, \text{ I}_{D} = 3 \text{ A},$ $V_{GS} = 10 \text{ V}$ (see <i>Figure 21</i>)	-	10 3 4.7	14	nC nC nC

1. Pulsed: Pulse duration = 300 μ s, duty cycle 1.5 %.



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} ⁽¹⁾	Source-drain current Source-drain current (pulsed)		-		3 12	A A
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 3 A, V _{GS} = 0	-		1.5	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 3 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$ $V_{DD} = 100 \text{ V}, \text{ T}_{j} = 25^{\circ}\text{C}$ (see <i>Figure 17</i>)	-	224 1 9		ns nC A
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 3 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$ $V_{DD} = 100 \text{ V}, \text{ T}_{j} = 150^{\circ}\text{C}$ (see <i>Figure 17</i>)	-	296 1.4 9.3		ns μC Α
 Pulse width limited by safe operating area. Pulsed: Pulse duration = 300 μs, duty cycle 1.5 % Table 8. Gate-source Zener diode ⁽¹⁾ 						
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit

Table 7. Source drain diode

Gate-source Zener diode (1) Table 8.

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
BV _{GSO}	Gate-source breakdown voltage	I _{gs} =± 1mA (open drain)	30	-	-	V

 The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the Jon i Jone usage of external components.



Thermal impedance for TO-220

2.1 Electrical characteristics (curves)

Figure 3.

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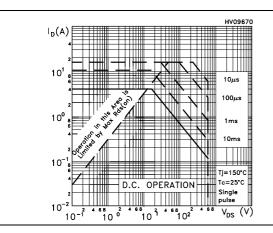
10

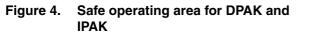
 10^{-2}

10⁻⁵

 $\delta = 0.$

Figure 2. Safe operating area for TO-220





Ш

D.C.

OPERATION

HV09680

10µs

100µs

Tj=150*

Tc=25°C

 V_{DS} (V)

Single



 10^{-2}

 10^{-3}

0.01

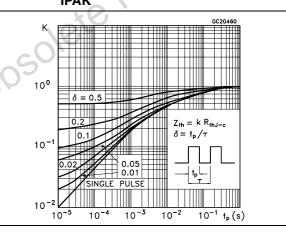
SINGLE PULSE

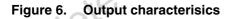
10-4

 $Z_{th} = k R_{thJ-c}$

 $10^{-1} t_{p}(s)$

 $\delta = t_p / \tau$





 $|_{D}(A)$

10¹

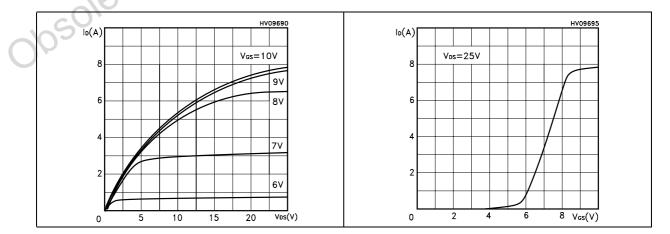
10⁰

10

10⁻²

 10^{-1}







Static drain-source on resistance

Figure 8. Transconductance

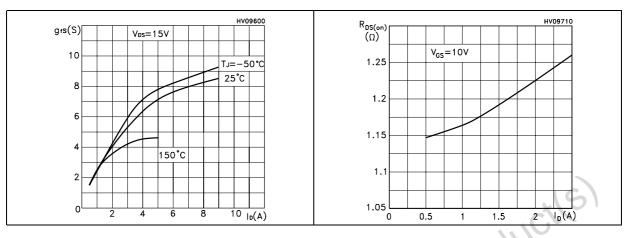


Figure 9.

Figure 10. Gate charge vs gate-source voltage Figure 11. Capacitance variations

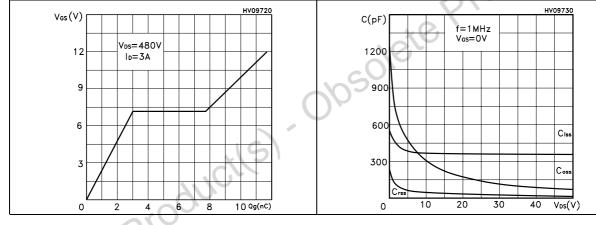
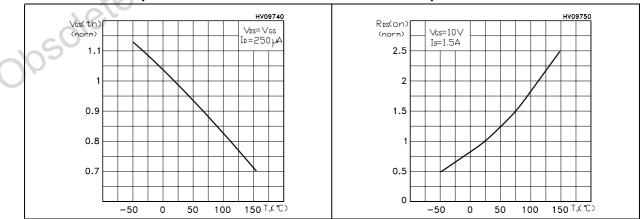


Figure 12. Normalized gate threshold voltage vs temperature

Figure 13. Normalized on resistance vs temperature



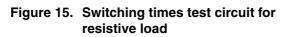


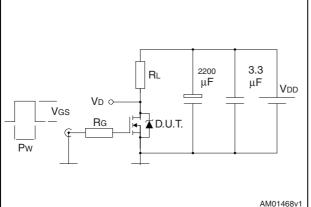
	HV09760
Vsd(V	
0.	
0.	25°
0.	
0.	150 °C
0.	
	16
0.	
	×C
	\mathbf{O}^{*}
	16
	G^{\times}
	x (2)
10	
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Figure 14. Source-drain diode forward characteristics



3 Test circuits





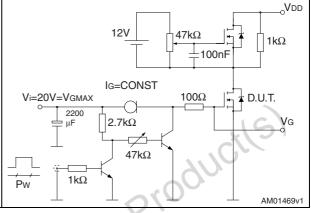
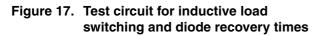
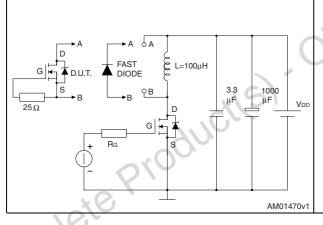


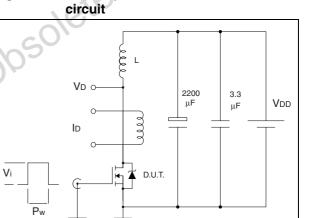
Figure 18. Unclamped inductive load test

Figure 16. Gate charge test circuit

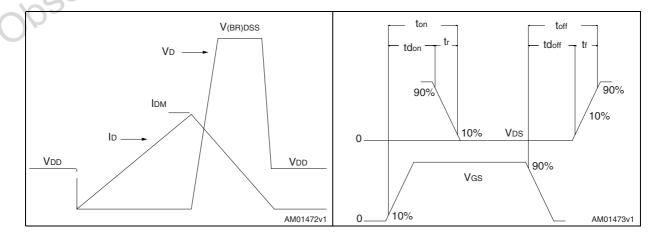












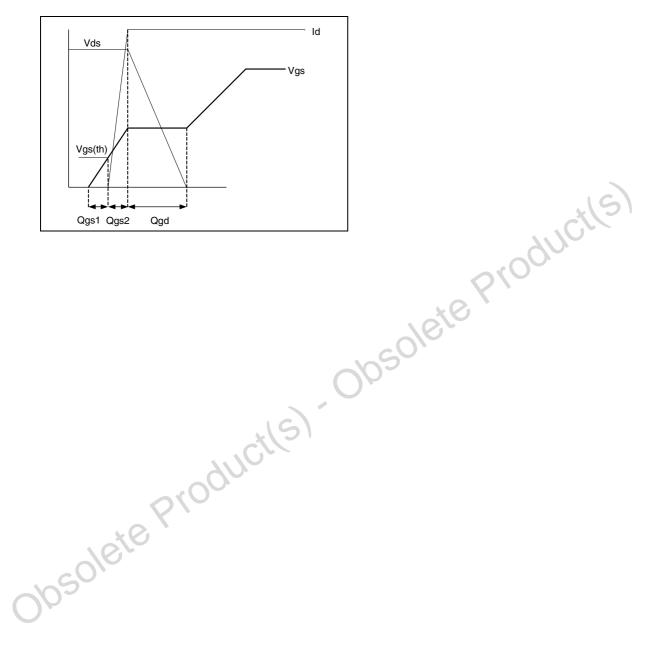


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Figure 21. Gate charge waveform



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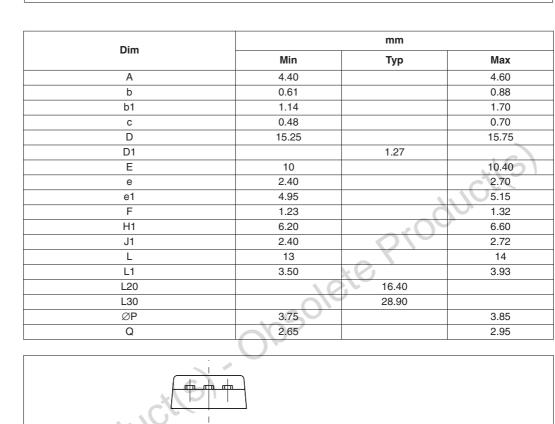


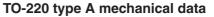
4 Package mechanical data

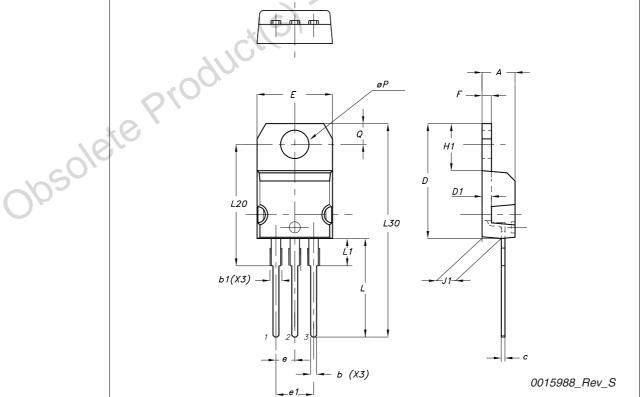
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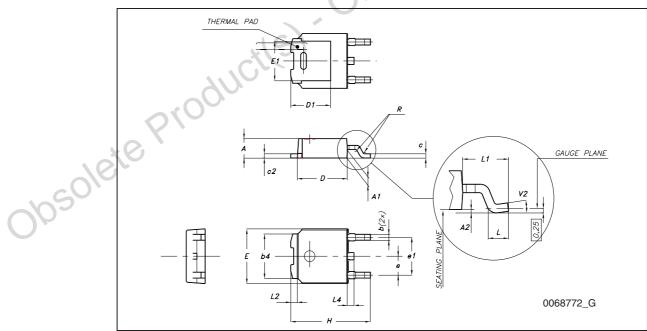






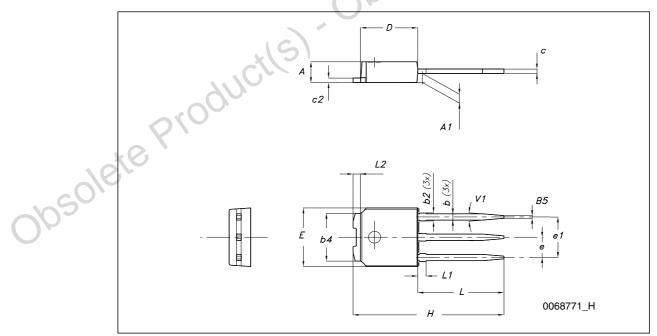


	10-252 (D	PAK) mechanical data		
DIM.	mm.			
	min.	typ	max.	
A	2.20		2.40	
A1	0.90		1.10	
A2	0.03		0.23	
b	0.64		0.90	
b4	5.20		5.40	
с	0.45		0.60	
c2	0.48		0.60	
D	6.00		6.20	
D1		5.10	16	
E	6.40		6.60	
E1		4.70		
е		2.28	20-	
e1	4.40		4.60	
Н	9.35		10.10	
L	1		~	
L1		2.80		
L2		0.80		
L4	0.60		1	
R		0.20		
V2	0 °		8 ^o	





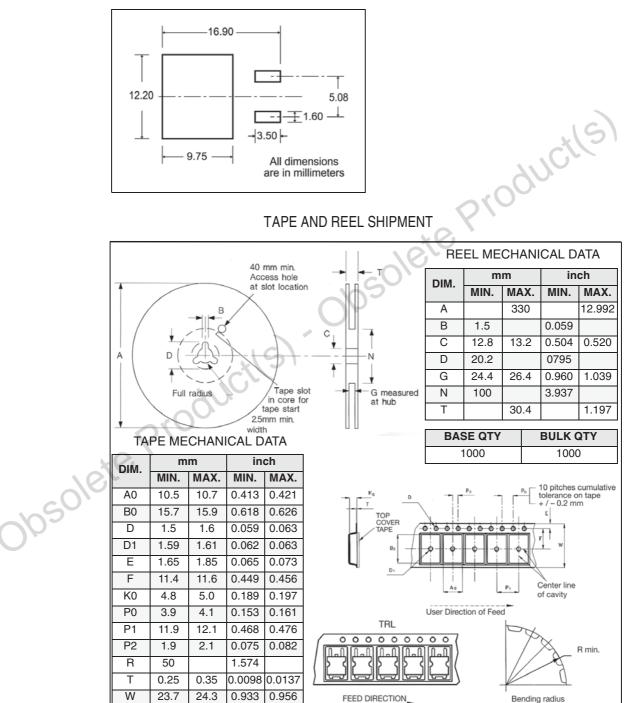
DIM.	mm.			
	min.	typ	max.	
A	2.20		2.40	
A1	0.90		1.10	
b	0.64		0.90	
b2			0.95	
b4	5.20		5.40	
с	0.45		0.60	
c2	0.48		0.60	
D	6.00		6.20	
E	6.40		6.60	
е		2.28	20-	
e1	4.40		4.60	
Н		16.10		
L	9.00	. 0.	9.40	
(L1)	0.80	101	1.20	
L2		0.80		





5 Packaging mechanical data





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6 Revision history

Table 9.Document revision history

	Date	Revision	Changes
	14-Jan-2004	3	
	02-Sep-2009	4	Inserted V _{DSS} value @ T _{jmax} = 150 °C on cover page Document reformatted to improve readability
obsole	tepro	Jucil	obsolete

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